Probing molecular layers with low-energy electrons

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Citation

Tebyani, A. (2024, March 14). *Probing molecular layers with low-energy electrons*. Retrieved from https://hdl.handle.net/1887/3721791

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Probing Molecular Layers with Low-Energy Electrons

Proefschrift

ter verkrijging van
de graad van doctor aan de Universiteit Leiden,
op gezag van rector magnificus prof.dr.ir. H. Bijl,
volgens besluit van het college voor promoties
te verdedigen op donderdag 14 maart 2024
klokke 16.15 uur

door

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geboren te Tehran, Iran
in 1990

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ISBN: 978-94-6496-069-3

An electronic version of this dissertation is available at: https://openaccess.leidenuniv.nl

The work presented in this dissertation was funded by the Dutch Research Council (NWO) as part of the Frontiers of Nanoscience program.

Cover illustration by Steffie Padmos, www.steffiepadmos.com

The cover depicts the experimental setup. In a Low-Energy Electron Microscope, a beam of electrons is emitted from an electron gun at the top, and is directed to the sample, i.e. molecular layers. After interaction with the sample, the reflected electrons are collected and guided to the detector at the bottom, where they form an image.

Printed by: Gildeprint – Enschede

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